

**Notice of References Cited**

Application/Control No.

10/712,788

Applicant(s)/Patent Under  
Reexamination  
DELMULLE ET AL.

Examiner

Yuwen Pan

Art Unit

2618

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0122810	06-2004	Mayer, Yaron	707/003
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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**FOREIGN PATENT DOCUMENTS**

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